

<b>Notice of References Cited</b>	Application/Control No. 10/784,502		Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL.	
	Examiner YOUNG T. TSE		Art Unit 2611	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,930,244 A	07-1999	Ariyoshi et al.	370/335
*	B	US-2003/0215005 A1	11-2003	Kontola et al.	375/149
	C	US-			
	D	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

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